

## AFM Zoom Option for 3D Optical Microscopes



Bruker Corp. has introduced the NanoLens atomic force microscope (AFM) accessory for ContourGT 3D optical microscopes. Designed for fast installation on a five-position, automated turret, the NanoLens delivers high-resolution imaging capabilities without sacrificing measurement speed in optical modes. With NanoLens, users can perform nanometer-scale surface and material property analysis on the same system that provides repeatable 3D optical microscopy measurements. The NanoLens allows users to augment the large field of view, high throughput, and z-axis resolution of Bruker's ContourGT systems with the higher lateral 1,000x resolution of an AFM.

**Bruker Corp.**, [www.bruker.com](http://www.bruker.com) [1]

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[1] <http://www.bruker.com/>